

Application specific true critical paths identification in sequential circuits

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan; Devadze, Sergei; Oyeniran, Adeboye Stephen 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 299-304 : ill <https://doi.org/10.1109/IOLTS.2019.8854442>

Fast identification of true critical paths in sequential circuits

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Hierarchical timing-critical paths analysis in sequential circuits

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A scalable technique to identify true critical paths in sequential circuits

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